
Self-test configuration for SPC58xEx and SPC58xGx devices

Introduction

This document provides the guidelines about how to configure the self-test control unit (STCU2) and start the self-test execution.

The STCU2 on SPC58xEx and SPC58xGx devices manages both Memory and Logic Built-In Self Test (MBIST and LBIST) of the device. The MBISTs and LBISTs can detect latent failures which affect the volatile memories and the logic modules.

The reader should have a clear understanding of the usage of self-test, for additional details see [Reference documents](#).

1 Overview

The SPC58xEx and SPC58xGx support both the MBIST and LBIST.

The SPC58xEx and SPC58xGx include:

- 102 memory cuts
- LBIST0 (the safety LBIST)

Moreover, SPC58xEx includes also 6 LBIST for diagnostic (from 1 to 6).

Note: LBIST for diagnostic should run when the vehicle is in the garage and not while the safety application is running.

The reader can consult the complete list on the chapter 7 (Device configuration) of the [RM0391](#) SPC58xEx and SPC58xGx reference manual.

2 Self-test configuration

Self-test can run either in online or offline mode.

2.1 MBIST configuration

To reach the best trade-off in terms of consumption and execution time, we recommend dividing the MBISTs into 12 splits. The MBIST partitions belonging to the same split run in parallel.

The 12 splits run in sequential mode. For example:

- all MBIST partitions belonging to the split_0 start in parallel;
- after their execution, all MBIST partitions belonging to the split_1 start in parallel;
- and so forth.

The complete list of the splits and MBISTs is shown in the split and DCF Microsoft Excel® workbook attached files.

2.2 LBIST configuration

In offline mode, generally only the LBIST0 runs, that is the safety BIST (to guarantee the ASIL D). It is the first BIST in the self-test configuration (pointer 0 in the LBIST_CTRL register).

In the case of SPC58xEx, in online mode the user can choose to run the other LBISTs (from 1 to 6) for diagnostic use. They include:

- LBIST1: gtm
- LBIST2: hsm, sent, emios0, psi5, dsp
- LBIST3: can1, flexray_0, memu, emios1, psi5_0, fccu, ethernet1, adcsd_x, crc_0, crc_1, fosu, cmu_x, bam
- LBIST4: psi5_1, ethernet0, adcsar_x, iic, dsp_x, adcsar_dig_x, adcsar_seq_x, linlfex_x, pit, ima, cmu_x
- LBIST5: platform
- LBIST6: can0, dma

2.3 DCF list for offline configuration

MBISTs and LBIST0 can run in offline up to 100 MHz as max frequency. The DCF Microsoft Excel® workbook attached file reports the list of the DCF to be configured in order to start up the MBIST and LBIST during the boot phase (offline mode). They take around 42 ms.

2.4 Monitors during self-test

Two different phases impact the self-test execution (See RM0421 SPC58xNx reference manual).

- **Initialization (configuration loading).** The SSCM (offline mode) or the software (online mode) configures the BISTs by programming the STCU2.
- **Self-test execution.** The STCU2 executes self-test.

Two different watchdogs monitor these phases.

1. **Hard-coded watchdog** monitors the “initialization” phase. It is a hardware watchdog configured at 0x3FF. The user cannot modify it. The clock of the hard-coded watchdog depends on the operating mode:
 - IRC oscillator in offline mode
 - STCU2 clock in online mode
2. **Watchdog timer (WDG)** monitors the “self-test execution”. It is a hardware watchdog configurable by the user (STCU_WDG register). The user can check the status of the “STCU WDG” after the BIST execution in the STCU_ERR_STAT register (WDTO flag).

The clock of “STCU WDG” depends on the operating mode:

- It is configurable by the STCU_PLL (IRC or PLL0) in offline mode;
- It is configurable by software in online mode.

2.4.1 Hard-coded watchdog refresh during initialization

The hard-coded watchdog timeout is 0x3FF clock cycles. The SSCM or the software must periodically refresh the hard-coded watchdog by programming the STCU2 key2. To perform this operation, the user must interleave the list of DCF records (offline mode) or the writing accesses to the STCU2 registers (online mode) with a write to the STCU2 key2 register. In the case of offline BIST, a single write of a DCF record takes around 17 clock cycles.

Since the hard-coded watchdog expires after 1024 clock cycles, the user must refresh it every 60 DCF records.

Note: *The watchdog expires after 1024 clock cycles. A single DCF write takes 17 clock cycles. The STCU2 accepts up to 60 DCF records before the hard-watchdog expires ($1024/17 = 60$).*

In the case of online BIST, the refresh time (STCU2 key2 writing) is application dependent.

2.5 Online mode configuration

In online mode the MBIST split list remains the same with some limitations due to life cycle. All MBISTs can run in online mode only in ST production and Failure Analysis (FA). In the other Life Cycles, HSM /MBIST and FLASH MBIST are not accessible. In this case, the maximum frequency for MBIST 180 MHz, is provided by the sys_clock.

The LBIST for diagnostic can run up to 35 MHz, while LBIST 0 can run up to 100 MHz. In that case, STCU registers can be configured with the "register value" column of the DCF list file.

3 Summary

In the SPC58xEx and SPC58xGx both MBIST and LBIST can run. During offline, LBIST0 and all MBISTs can run according to the split configuration. The SPC58xEx includes also the diagnostic BIST that can be executed during the online mode.

Appendix A Acronyms, abbreviations and reference documents

Table 1. Acronyms

Acronym	Name
MBIST	Memory Built-In Self Test
LBIST	Logic Built-In Self Test
STCU2	Self-test control unit
HSM	Hardware system module
LC	Life cycle
DCF	Device configuration format (DCF) records
UTest	User test flash block
FA	Failure analysis

Table 2. Reference documents

Document name	Document title
RM0391	SPC58xEx/SPC58xGx 32-bit Power Architecture® microcontroller for automotive ASILD applications
AN4551	SPC574K72xx self-test procedures

The split and DCF settings are contained in the Microsoft Excel® workbook files attached to this document. Locate the paperclip symbol on the left side of the PDF window, and click it. Double-click on the Excel file to open it.

Revision history

Table 3. Document revision history

Date	Revision	Changes
30-Jun-2020	1	Initial release.
13-Apr-2022	2	<p>Updated title on cover page.</p> <p>Added Section 2.4 Monitors during self-test and Section 2.4.1 Hard-coded watchdog refresh during initialization.</p> <p>Updated split and DCF Microsoft Excel® workbook attached files.</p> <p>Minor text changes.</p>

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